




<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>09774715</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>IWAMURA ET AL.</p>
	<p>Examiner</p> <p>Mills, Donald L</p>	<p>Art Unit</p> <p>2616</p>

Class	SubClass	Date	Examiner
370	230, 230.1, 232, 233, 395.2, 395.21, 468	08/02/2006	DLM

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<b>Search Notes</b>  	Application/Control No.  09774715	Applicant(s)/Patent Under Reexamination  IWAMURA ET AL.
	Examiner Mills, Donald L	Art Unit 2616

Notes	Date	Examiner
EAST (US PGPUBS, USPATs, EPO, JPO, IBM, DERWENT)	08/02/2006	DLM
IEEE - <a href="http://ieeexplore.org">ieeexplore.org</a> - ATM	08/02/2006	DLM
Internet - <a href="http://google.com">google.com</a> - ATM	08/02/2006	DLM
John Pezzlo (consulted)	08/04/2006	DLM
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<b>Interference Searched</b>  	Application/Control No.  09774715	Applicant(s)/Patent Under Reexamination  IWAMURA ET AL.
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